



[40103/00501]

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Inventor(s) : James HARRISON et al.
 Serial No. : 10/033,975
 Filing Date : December 19, 2001
 For : IMPROVED METHOD AND APPARATUS FOR
 WAFER-LEVEL TESTING OF SEMICONDUCTOR
 LASERS
 Group Art Unit : 2858

Commissioner of Patents
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By: *Patrick J. Fay* Date: *February 8, 2002*

RESPONSE TO NOTICE TO FILE MISSING PARTS OF
NONPROVISIONAL APPLICATION

SIR:

Transmitted herewith for filing in the above-identified application is a Response to the Notice to File Missing Parts of NonProvisional Application mailed January 29, 2002. To complete the filing requirements of the NonProvisional application, herewith please find an executed Declaration and Power of Attorney and check in the amount of \$65.00.

Please charge **any deficiency** therein, to Fay Kaplun & Marcin, LLP's Deposit Account No. **50-1492**. A copy is enclosed for this purpose.

Respectfully submitted,

By: *Patrick J. Fay*
 Patrick J. Fay, Reg. No. 35,508

Dated: *February 8, 2002*

Fay Kaplun & Marcin, LLP
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UNITED STATES PATENT AND TRADEMARK OFFICE

COMMISSIONER FOR PATENTS
UNITED STATES PATENT AND TRADEMARK OFFICE
WASHINGTON, D.C. 20231
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APPLICATION NUMBER	FILING/RECEIPT DATE	FIRST NAMED APPLICANT	ATTORNEY DOCKET NUMBER
10/033,975	12/19/2001	James Harrison	40103/00501

CONFIRMATION NO. 9121
FORMALITIES LETTER

FAY KAPLUN & MARCIN, LLP
17th Floor
100 Maiden Lane
New York, NY 10038



OC00000007384670

Date Mailed: 01/29/2002

NOTICE TO FILE MISSING PARTS OF NONPROVISIONAL APPLICATION

FILED UNDER 37 CFR 1.53(b)

Filing Date Granted

An application number and filing date have been accorded to this application. The item(s) indicated below, however, are missing. Applicant is given **TWO MONTHS** from the date of this Notice within which to file all required items and pay any fees required below to avoid abandonment. Extensions of time may be obtained by filing a petition accompanied by the extension fee under the provisions of 37 CFR 1.136(a).

- The oath or declaration is missing.
A properly signed oath or declaration in compliance with 37 CFR 1.63, identifying the application by the above Application Number and Filing Date, is required.
- To avoid abandonment, a late filing fee or oath or declaration surcharge as set forth in 37 CFR 1.16(l) of \$65 for a small entity in compliance with 37 CFR 1.27, must be submitted with the missing items identified in this letter.
- **The balance due by applicant is \$ 65.**

A copy of this notice MUST be returned with the reply.

C. J. Harrison

Customer Service Center

Initial Patent Examination Division (703) 308-1202

PART I - ATTORNEY/APPLICANT COPY

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FEB 07 2001

Recd 1/14/02
#4



U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

REQUEST FOR CORRECTED FILING RECEIPT

ATTORNEY'S DOCKET NO.
40103/00501

APPLICATION NO. 10/033,975	FILING DATE December 19, 2001	EXAMINER	ART UNIT 2858
INVENTION TITLE IMPROVED METHOD AND APPARATUS FOR WAFER-LEVEL TESTING OF SEMICONDUCTOR LASERS		INVENTOR(S) James HARRISON et al.	

Address to:

Commissioner of Patents
P.O. Box 2327
Arlington, VA 22202

Applicant respectfully requests that the Filing Receipt be corrected to indicate the Title of this application as **IMPROVED METHOD AND APPARATUS FOR WAFER-LEVEL TESTING OF SEMICONDUCTOR LASERS**.

Please issue a corrected Filing Receipt as requested above. As this correction was necessitated by a Patent Office error, no fees are believed to be required. However, if any fees are required, please use the deposit account of **Fay Kaplun & Marcin, LLP**, deposit account number **50-1492**. A copy of this sheet is enclosed for that purpose.

Dated:

February 8, 2002

By:

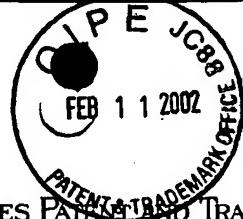

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Date: 2/8/02

1-100-35,508

Signature: Tesla Ramos



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APPLICATION NUMBER	FILING DATE	GRP ART UNIT	FIL FEE REC'D	ATTY.DOCKET.NO	DRAWINGS	TOT CLAIMS	IND CLAIMS
10/033,975	12/19/2001	2858	553	40103/00501	3	31	5

CONFIRMATION NO. 9121

FILING RECEIPT



OC00000007384669

FAY KAPLUN & MARCIN, LLP
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New York, NY 10038

Date Mailed: 01/29/2002

Receipt is acknowledged of this nonprovisional Patent Application. It will be considered in its order and you will be notified as to the results of the examination. Be sure to provide the U.S. APPLICATION NUMBER, FILING DATE, NAME OF APPLICANT, and TITLE OF INVENTION when inquiring about this application. Fees transmitted by check or draft are subject to collection. Please verify the accuracy of the data presented on this receipt. If an error is noted on this Filing Receipt, please write to the Office of Initial Patent Examination's Customer Service Center. Please provide a copy of this Filing Receipt with the changes noted thereon. If you received a "Notice to File Missing Parts" for this application, please submit any corrections to this Filing Receipt with your reply to the Notice. When the USPTO processes the reply to the Notice, the USPTO will generate another Filing Receipt incorporating the requested corrections (if appropriate).

Applicant(s)

James Harrison, Residence Not Provided;
David Heald, Residence Not Provided;

Domestic Priority data as claimed by applicant

Foreign Applications

If Required, Foreign Filing License Granted 01/29/2002

Projected Publication Date: To Be Determined - pending completion of Missing Parts

Non-Publication Request: No

Early Publication Request: No

** SMALL ENTITY **

Title

Improved Method and apparatus for wafer-level testing of semiconductor laser

Preliminary Class

324

FEB 07 2001